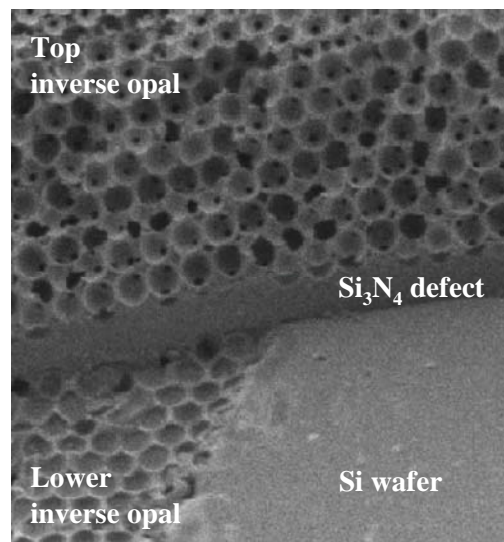
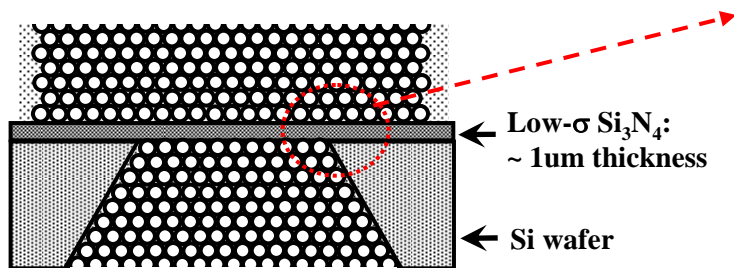


# Planar Defect Embedded in Inverse Opals

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NNIN Facility utilized: Nanofabrication Center



**Cross sectional view:**  
top inverse opal layer  
&  $\text{Si}_3\text{N}_4$  defect

**Top surface view:**  
lower inverse opal layer  
& Si wafer

